Supporting Information for

Phosphorus- and Sulfur-Containing High Refractive Index Polymers with High T_g and Transparency Derived from A Bio-based Aldehyde

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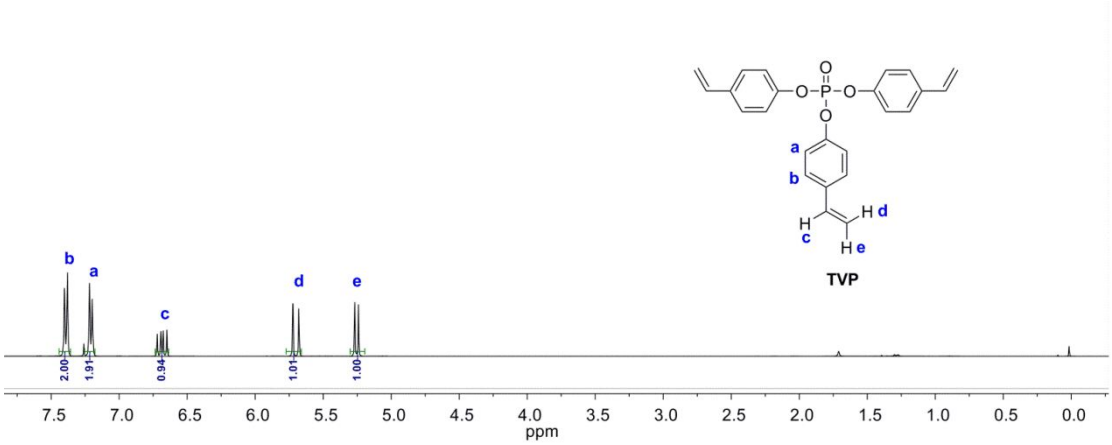

Figure S1. ^{1}H NMR spectrum of **TVP** (400 MHz, $CDCl_3$).

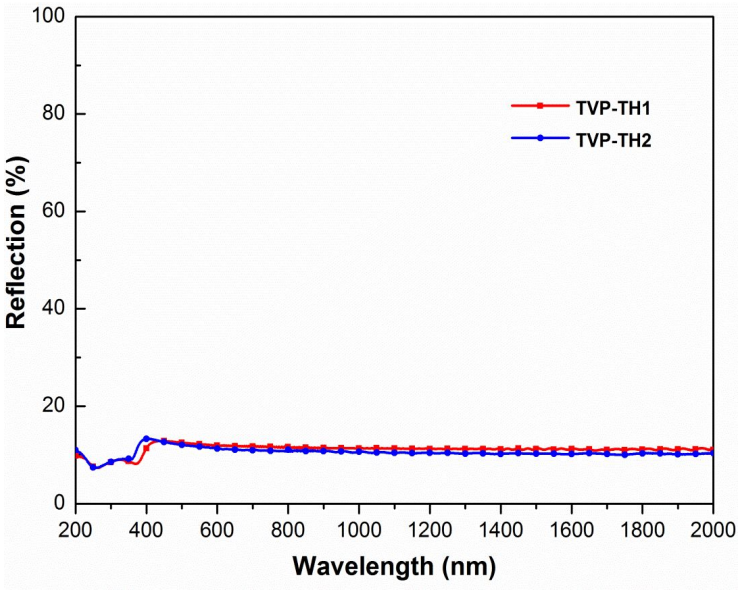

Figure S2. Reflection spectra of free-standing films of **TVP-TH1** and **TVP-TH2.**

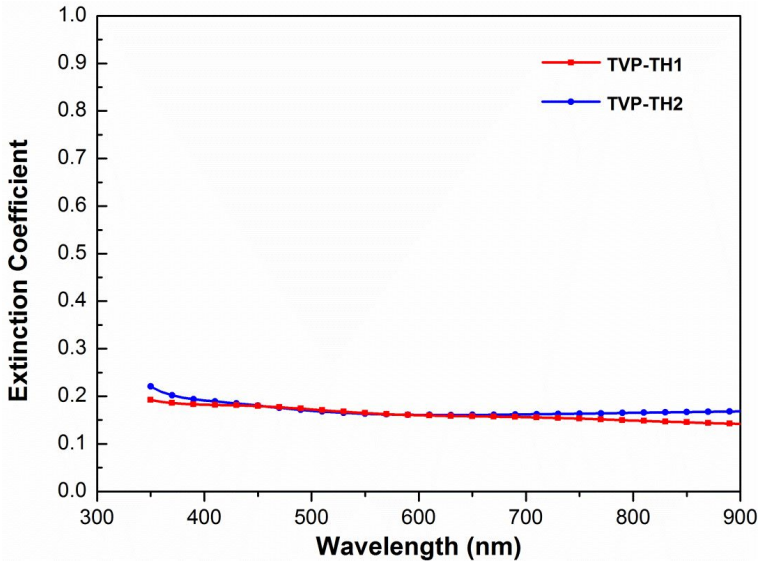

Figure S3. Variation coefficient of the extinction coefficient of the **TVP-TH1** and **TVP-TH2.** films.

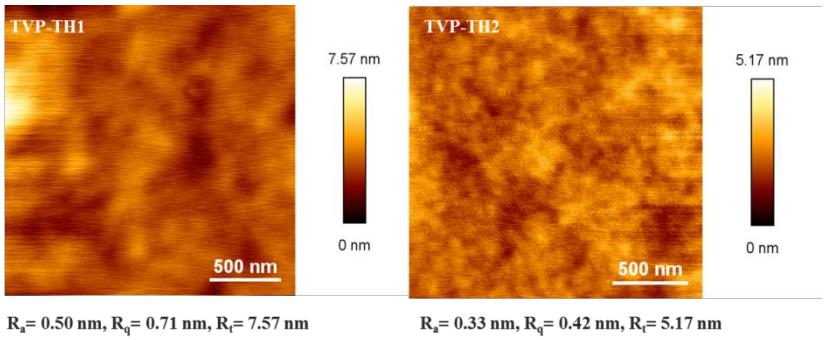

Figure S4. AFM images of **TVP-TH1** and **TVP-TH2** films on silicon wafers.

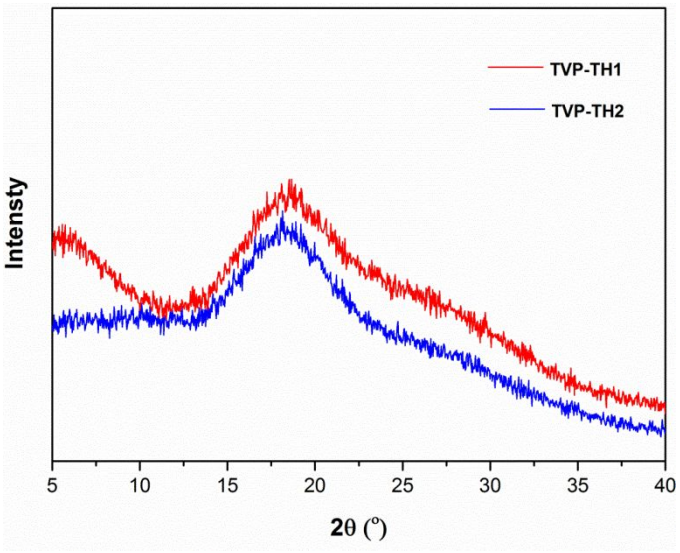

Figure S5. XRD pattern of free-standing films of **TVP-TH1** and **TVP-TH2.**